

U.S. PATENT DOCUMENTS					
EXAMINER: (Use several sheets if necessary)					
APPLICATIONS Shigeaki HAYASHI et al.					
U.S. PATENT DOCUMENTS					
EXAMINER DINITIAL					
1	5,927,750	07/27/1999	NAKAMURA et al.	NAME	CLASS
DOCUMENT NUMBER DATE COUNTRY SUB CLASS					
2	WO 00/46076	08/10/2000	WIPO		
3 JP A 2003-501303 w/absrt. & trans. 01/14/2003 JAPAN					
4 JP U 3013763 w/translation 05/10/1995 JAPAN					
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EXAMINER /Floan F/o/ DATE CONSIDERED 08/14/2008					
Examiner: Initial if citation considered, whether or not citation is in conformance with M.P.E.P. 609; draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.					

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